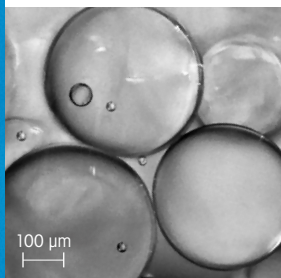
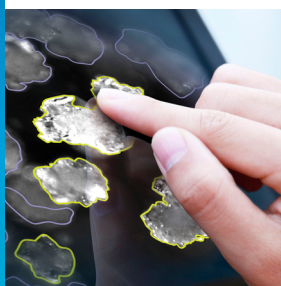


View and Measure Particles In Situ and in Real Time



New Experimental Insights

Capture high-resolution images of particles, crystals, and droplets as they exist in situ, to obtain deep process understanding for complex chemical systems. Study crystallization, precipitation, suspensions, and emulsions at previously unobtainable levels of detail, revealing new insights to power process-development decision-making.



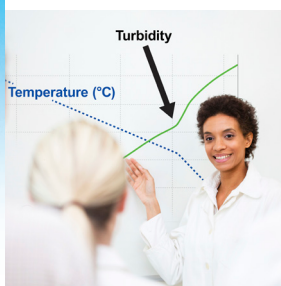
Powerful Analytics

Transform EasyViewer into a powerful particle size analyzer using image analysis methods in iC Vision. Monitor process changes using simple analytics or quantify particle size and shape with customized algorithms. Verify results by comparing data with collected images and use this combined information to design the right particles, faster.



Flexibility for Scale-up

EasyViewer 400 works in the lab or plant thanks to a small, probe-only instrument and flexible mounting system that inserts in to reactors, pilot vessels, and pipelines. Characterization conducted at smaller scales can be compared directly to results obtained during scale-up and transfer de-risking late stage process development.



Confident Deployment

Leverage auto-focus, auto-lighting, and auto-save-best-image software features to ensure every team member collects the highest-quality images from beginning to end of every experiment, so that you never miss anything.



EasyViewer 400

EasyViewer™ 400 is a probe-based imaging tool that captures high-resolution images of crystals, particles, and droplets as they exist in-process. Combined with iC Vision™, an easy-to-use image analysis software, EasyViewer becomes a powerful particle size analyzer that can monitor process changes and quantify particle size and shape in real time. EasyViewer can characterize particle processes across scales, supporting process scale-up, transfer and production. Exceptional information combined with broad usability makes EasyViewer a compelling tool that scientists will enjoy using to accelerate decision-making and speed process-development and scale-up.

METTLER TOLEDO

View and Measure Particles

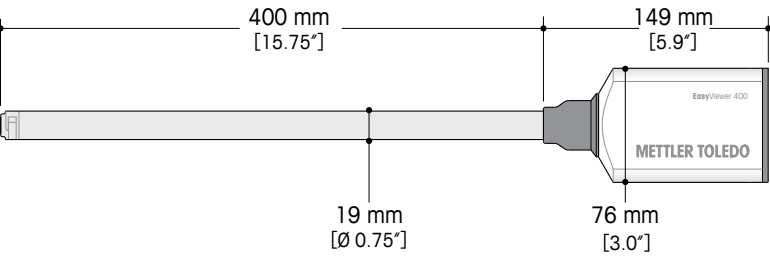
In Situ and in Real Time

Technical Data

Probe Wetted Material	C22 Alloy, PTFE, Sapphire
Probe Window Material	Sapphire
Probe Diameter	19 mm [0.75 in]
Probe Wetted Length	400 mm [15.75 in]
USB Cable Length	3 m [9.8 ft] (standard)
Field of View	1100 µm x 800 µm (± 50 µm)
Optical Resolution	> 980 nm
Laser Wavelength	450 nm
Lighting Modes	Front, Back
Probe Weight	1.45kg [3.2 lbs]
Probe Wetted Temperature Range	10 °C to 100 °C (standard) 10 °C to 150 °C (custom) -80 °C to 100 °C (standard purged) -80 °C to 150 °C (custom purged)
Probe Back End Temperature Range	0 °C to 40 °C (inserted to 300 mm) 0 °C to 25 °C (inserted to 400 mm)
Probe Wetted Pressure Range	Up to 10 barg (standard); Up to 80 barg (custom)
Air Requirements (use to avoid condensation when operating below dew point)	2.0 barg [30 psig]; 0.5 SLPM (0.02 SCFM) (clean, dry instrument-quality air or Nitrogen purge gas)
Certification	CE/NRTL-C Approved, Class 1 Laser Device, Compliant with 21CFR1040.10 and 1040.11 and IEC 60825-1.

EasyViewer 400 is not rated for explosive locations.

Probe Dimensions



www.mt.com/EasyViewer

For more information

METTLER TOLEDO Group
Automated Reactors and In-Situ Analysis
Local contact: www.mt.com/contacts

Subject to technical changes
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